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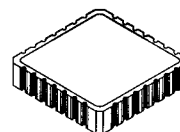
Designer's Data Sheet

FEATURES:

- Rugged construction with poly silicon gate
- Low RDS(on) and high transconductance
- Excellent high temperature stability
- Very fast switching speed
- Fast recovery and superior dv/dt performance
- Increased reverse energy capability
- Low input and transfer capacitance for easy paralleling
- Hermetically sealed surface mount package
- TX, TXV and Space Level screening available
- Replaces: IRF140 Types

**28*AMP
100 VOLT
0.095 Ω
N-CHANNEL
POWER MOSFET**

28 PIN CLCC



MAXIMUM RATINGS

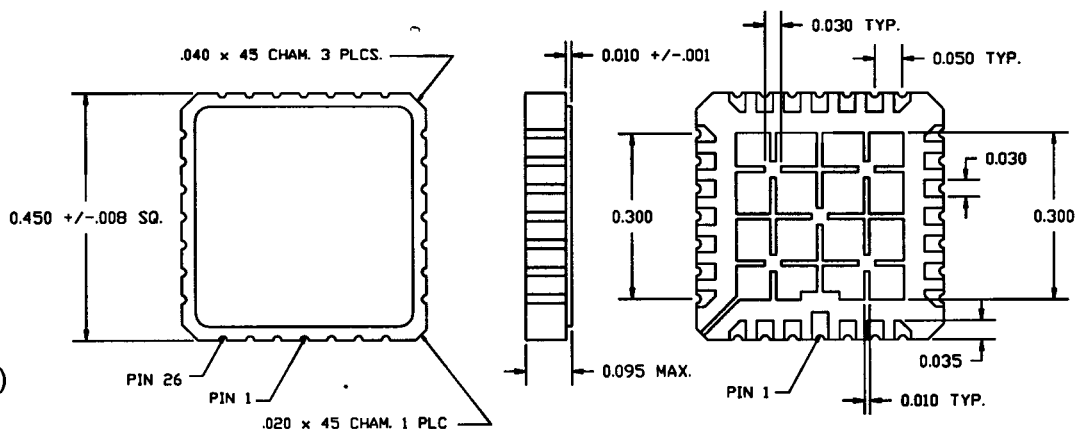
CHARACTERISTIC	SYMBOL	VALUE	UNIT
Drain to Source Voltage	V _{DS}	100	Volts
Gate to Source Voltage	V _{GS}	±20	Volts
Continuous Drain Current	I _D	28*	Amps
Operating and Storage Temperature	T _{op} & T _{stg}	-55 to +150	°C
Thermal Resistance, Junction to Case	R _{θJC}	3.5	°C/W
Total Device Dissipation @ TC=25°C Total Device Dissipation @ TC=80°C	P _D	20* 20	Watts

PACKAGE OUTLINE: 28 PIN CLCC

PIN OUT:
SOURCE: 1, 15-28
DRAIN: 5-11
GATE: 2, 3, 13, 14

NOTE:

All Drain/Source Pins must be connected on the PC Board in order to maximize current capability and minimize RDS(on)



* Rating based on size of chip. Device rating may vary depending on mounting and heatsink conditions. Consult SSDI Marketing department for thermal derating details.

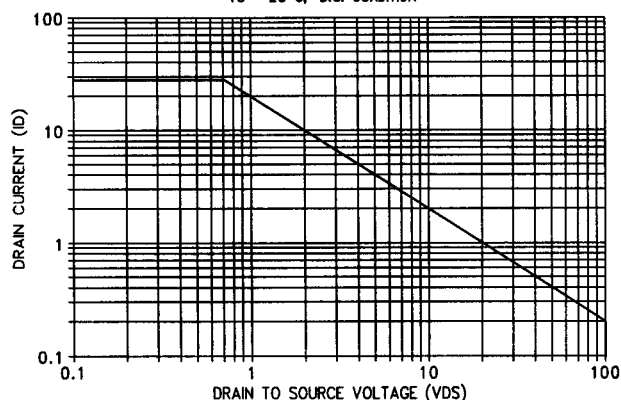
NOTE: All specifications are subject to change without notification. SCD's for these devices should be reviewed by SSDI prior to release.

DATA SHEET #: F00003 B

MED

ELECTRICAL CHARACTERISTICS @ $T_J=25^\circ\text{C}$ (Unless Otherwise Specified)

RATING		SYMBOL	MIN	TYP	MAX	UNIT
Drain to Source Breakdown Voltage ($V_{GS}=0\text{ V}$, $I_D=250\mu\text{A}$)		BV_{DSS}	100	---	---	V
Drain to Source on State Resistance ($V_{GS}=10\text{ V}$, $I_D=60\%$ Rated ID)		$R_{DS(on)}$	---	0.075	0.095**	Ω
On State Drain Current ($V_{DS}>I_D(on) \times R_{DS(on)}$ Max, $V_{GS}=10\text{ V}$)		$I_D(on)$	28*	---	---	A
Gate Threshold Voltage ($V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$)		$V_{GS(th)}$	2.0	---	4.0	V
Forward Transconductance ($V_{DS}>I_D(on) \times R_{DS(on)}$ Max, $I_{DS}=60\%$ rated ID)		g_{fs}	8.7	11	---	S(Ω)
Zero Gate Voltage Drain Current ($V_{DS}=\text{max rated voltage}$, $V_{GS}=0\text{ V}$) ($V_{DS}=80\%$ rated VDS, $V_{GS}=0\text{ V}$, $T_A=150^\circ\text{C}$)		I_{DSS}	---	---	250 1000	μA
Gate to Source Leakage Forward Gate to Source Leakage Reverse	At rated VGS	I_{GSS}	---	---	100 -100	nA
Total Gate Charge Gate to Source Charge Gate to Drain Charge	$V_{GS}=10\text{ Volts}$ 50% rated VDS Rated ID	Q_g Q_{gs} Q_{gd}	---	40 8 20	59 12 28	nC
Turn on Delay Time Rise Time Turn Off Delay Time Fall Time	$V_{DD}=50\%$ rated VDS rated ID $R_G=9.1\Omega$	$t_{d(on)}$ t_r $t_{d(off)}$ t_f	---	15 72 40 50	23 110 60 75	nsec
Diode Forward Voltage ($I_S=\text{rated ID}$, $V_{GS}=0\text{ V}$, $T_J=25^\circ\text{C}$)		V_{SD}	---	---	2.5	V
Diode Reverse Recovery Time Reverse Recovery Charge	$T_J=25^\circ\text{C}$ $I_F=10\text{A}$ $di/dt=100\text{ A}/\mu\text{sec}$	t_{rr} Q_{RR}	70 0.44	150 0.91	300 1.9	nsec μC
Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{GS}=0\text{ Volts}$ $V_{DS}=25\text{ Volts}$ $f=1\text{ MHz}$	C_{iss} C_{oss} C_{rss}	---	1500 500 90	---	pF

SAFE OPERATING AREA (S.O.A.)
 $T_C = 25^\circ\text{C}$, D.C. CONDITION**NOTES:**

* Rating based on size of chip. Device rating may vary depending on mounting and heatsink conditions. Consult SSDI Marketing department for thermal derating details.

** Due to package resistance; all Source/Drain pins must be connected on the PC Board in order to obtain the lowest $R_{DS(on)}$ possible.